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Supplementary Information

Effects of V and Gd doping on novel positive colossal electroresistance and quantum transport in PbPdO₂ thin films with (002) preferred orientation

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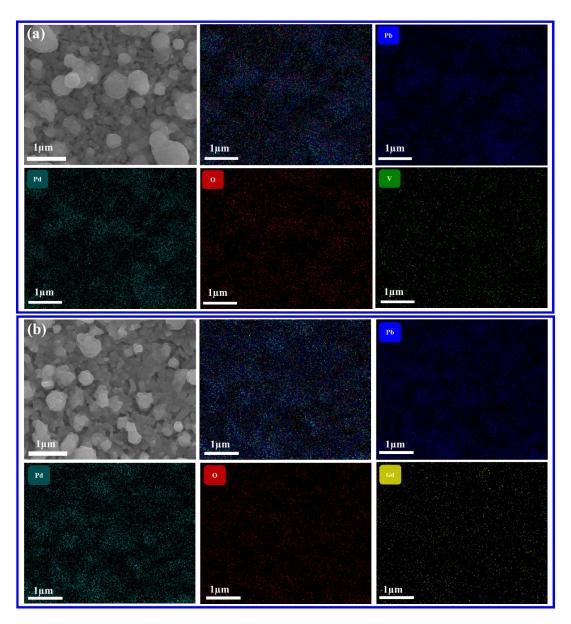
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1. EDS element mappings supplementary information



 $\textbf{Fig.S1} \ \ \text{EDS} \ \ element \ mappings \ images \ of (a) \ \ PbPd_{0.9}V_{0.1}O_2 \ \ and (b) \ \ PbPd_{0.9}Gd_{0.1}O_2 \ \ thin \ films.$

2. In-situ XPS supplementary information

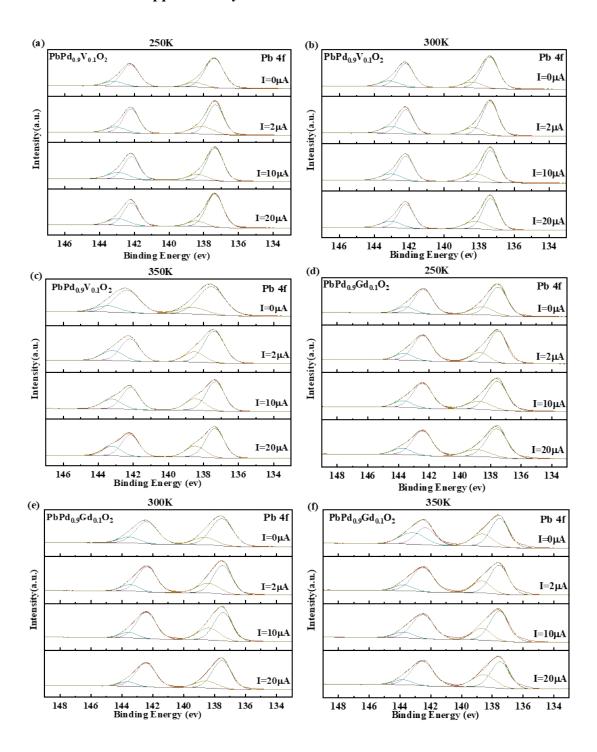


Fig. S2 (a)-(c) In-situ XPS of Pb 4f at T = 250 K, 300 K and 350 K for PbPd_{0.9}V_{0.1}O₂ thin film; (d)-(f) In-situ XPS of Pb 4f at T = 250 K, 300 K and 350 K for PbPd_{0.9}Gd_{0.1}O₂ thin film.

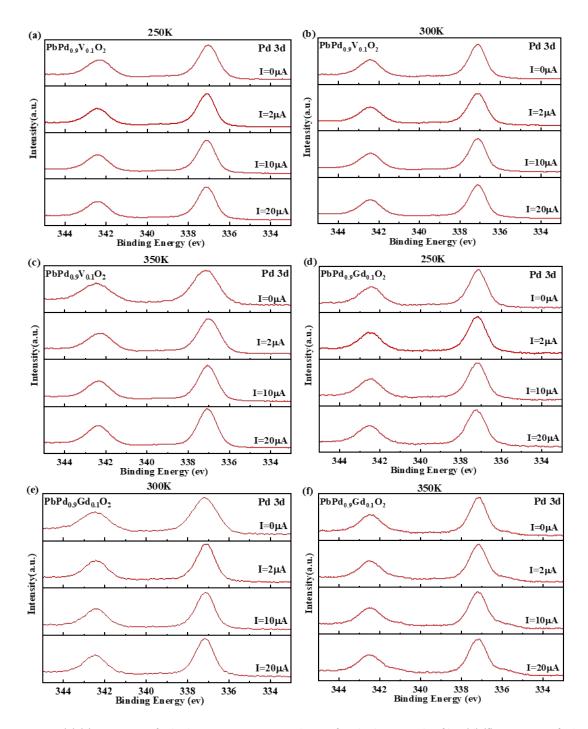


Fig. S3 (a)-(c) In-situ XPS of Pd 3d at T = 250 K, 300 K and 350 K for PbPd_{0.9}V_{0.1}O₂ thin film; (d)-(f) In-situ XPS of Pd 3d at T = 250 K, 300 K and 350 K for PbPd_{0.9}Gd_{0.1}O₂ thin film.